

Features

Туре	V _{DSS}	R _{DS(on)}	I _D
STS8C5H30L(N-channel)	30V	<0.022	8A
STS8C5H30L(P-channel)	30V	<0.056	5A

- Conduction losses reduced
- Switching losses reduced
- Low threshold drive
- Standard outline for easy automated surface mount assembly

Description

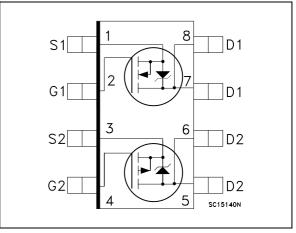
This Power MOSFET is the latest development of STMicroelectronics unique "Single Feature Size[™] strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

Application

Switching application

SO-8

Figure 1. Internal schematic diagram



Part number	Marking	Package	Packaging
STS8C5H30L	S8C5H30L	SO-8	Tape & reel

Note: For the P-channel MOSFET actual polarity of voltages and current has to be reversed

Contents

1	Electrical ratings
2	Electrical characteristics 4
	2.1 Electrical characteristics (curves)
3	Test circuit
4	Package mechanical data 11
5	Revision history



1 Electrical ratings

Table 2.	Absolute	maximum	ratings
	/		. a

Symbol	Parameter	Val	Unit	
Symbol			P-channel	Unit
V _{DS}	Drain-source voltage (v _{gs} = 0)	30)	V
V _{GS}	Gate- source voltage	±16	±16	V
I _D	Drain current (continuos) at $T_C = 25^{\circ}C$ single operating	8 4.2		А
I _D	Drain current (continuos) at T _C = 100°C single operating	6.4 3.1		А
I _{DM} ⁽¹⁾	Drain current (pulsed)	32 16.8		А
P _{TOT}	Total dissipation at $T_C = 25^{\circ}C$ dual operating Total dissipation at $T_C = 25^{\circ}C$ single operating	1. 2	W W	
T _{stg}	Storage temperature	-55 to	°C	
Тj	Operating junction temperature	15	°C	

1. Pulse width limited by safe operating area

Table 3. Thermal data

	Thermal resistance junction-ambient single operating	62.5	°C/W
R _{thj-a}	Thermal resistance junction-ambient dual operating	78	°C/W
Τ _Ι	Maximum lead temperature for soldering purpose	300	°C

Note:

For the P-channel MOSFET actual polarity of voltages and current has to be reversed

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

	On/on states						
Symbol	Parameter	Test conditions		Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown voltage	I _D = 250 μA, V _{GS} = 0	n-ch	30 30			V V
		V _{DS} = Max rating	p-ch n-ch	30		1	ν μΑ
I _{DSS}	Zero gate voltage Drain current (V _{GS} = 0)	V _{DS} =Max rating, T _C =125°C	p-ch			10	μA
I _{GSS}	Gate-body leakage	$V_{GS} = \pm 16V$	n-ch			±100	nA
.022	current (V _{DS} = 0)	$V_{GS} = \pm 16V$	p-ch			±100	nA
Veerus	Gate threshold voltage	V _{DS} = V _{GS} , I _D = 250µA	n-ch	1			V
V _{GS(th)}	Cale lifeshold vollage	$v_{DS} = v_{GS}$, $v_{D} = 250 \mu A$	p-ch	1	1.6	2.5	V
		V _{GS} = 10V, I _D = 4A	n-ch		0.018	0.022	Ω
Brach	Static drain-source on	$V_{GS} = 10V, I_{D} = 2.5A$	p-ch		0.045	0.055	Ω
R _{DS(on)}	resistance	$V_{GS} = 4.5V, I_{D} = 4A$	n-ch		0.020	0.025	Ω
		$V_{GS} = 4.5V, I_{D} = 2.5A$	p-ch		0.070	0.075	Ω

Table 4. On/off states

Table 5. Dynamic

Tuble 0.	Bynamie						
Symbol	Parameter	Test conditions		Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 15V, I_D = 4A$ $V_{DS} = 15V, I_D = 2.5A$	n-ch p-ch		8.5 10		s s
C _{iss}	Input capacitance		n-ch p-ch		857 1350		pF pF
C _{oss}	Output capacitance	V _{DS} = 25V, f = 1 MHz, V _{GS} = 0	n-ch p-ch		147 490		pF pF
C _{rss}	Reverse transfer capacitance		n-ch p-ch		20 130		pF pF
Qg	Total gate charge	N-channel V _{DD} =24V I _D =8A	n-ch p-ch		7 12.5	10 16	nC nC
Q _{gs}	Gate-source charge	V_{GS} =5V P-channel V _{DD} = 24V I _D = 4A	n-ch p-ch		2.5 5		nC nC
Q _{gd}	Gate-drain charge	V _{GS} = 5V (see Figure 27)	n-ch p-ch		2.3 3		nC nC

1. Pulsed: Pulse duration = $300 \ \mu$ s, duty cycle 1.5.

Note: For the P-channel MOSFET actual polarity of voltages and current has to be reversed

Symbol	Parameter	Test conditions		Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	N-channel $V_{DD} = 15V, I_D = 4A$ $R_G=4.7 \ \Omega, V_{GS} = 4.5V$ P-channel $V_{DD} = 15V, I_D = 2A$ $R_G=4.7 \ \Omega, V_{GS} = 4.5V$ <i>(see Figure 26)</i>	n-ch p-ch n-ch p-ch		12 25 14.5 35		ns ns ns ns
^t d(off) t _f	Turn-off delay time Fall time	$\label{eq:VDD} \begin{array}{l} \textbf{N-channel} \\ \textbf{V}_{DD} = 15 \textbf{V}, \textbf{I}_{D} = 4 \textbf{A} \\ \textbf{R}_{G} = 4.7 \ \Omega, \textbf{V}_{GS} = 4.5 \textbf{V} \\ \textbf{P-channel} \\ \textbf{V}_{DD} = 15 \textbf{V}, \textbf{I}_{D} = 2 \textbf{A} \\ \textbf{R}_{G} = 4.7 \ \Omega, \textbf{V}_{GS} = 4.5 \textbf{V} \\ (see \ Figure \ 26) \end{array}$	n-ch p-ch n-ch p-ch		23 125 8 35		ns ns ns ns

Table 6. Switching times

Table 7. Source drain diode

Symbol	Parameter	Test conditions		Min	Тур.	Max	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		n-ch p-ch n-ch p-ch			8 5 32 20	A A A A
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 8A, V_{GS} = 0$ $I_{SD} = 5A, V_{GS} = 0$	n-ch p-ch			1.5 1.2	V V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	N-channel $I_{SD} = 8A$, di/dt = 100A/µs $V_{DD}=15 V$,T _j =150 °C P-channel $I_{SD} = 5 A$, di/dt = 100A/µs $V_{DD}=15 V$, T _j =150 °C (see Figure 28)	n-ch p-ch n-ch p-ch n-ch p-ch		15 45 5.7 36 0.76 1.6		ns ns nC nC A A

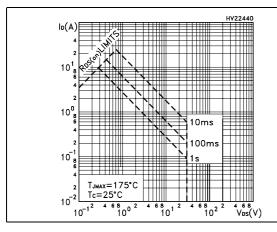
1. Pulse width limited by safe operating area.

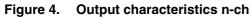
2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%

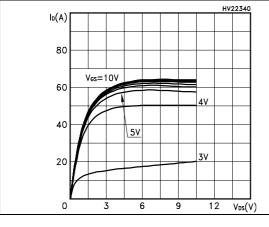


2.1 Electrical characteristics (curves)

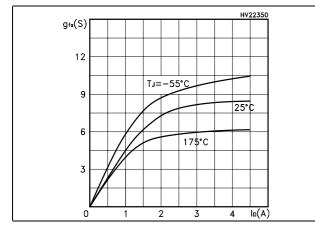
Figure 2. Safe operating area n-ch

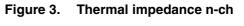












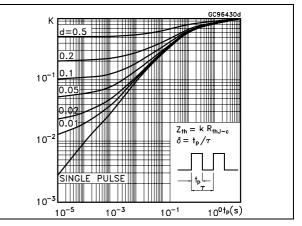


Figure 5. Transfer characteristics n-ch

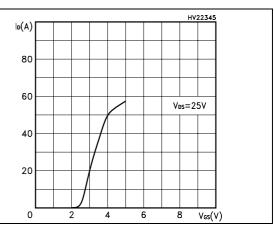
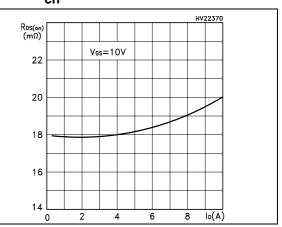


Figure 7. Static drain-source on resistance nch



57

Figure 8. Gate charge vs. gate-source voltage Figure 9. Capacitance variations n-ch

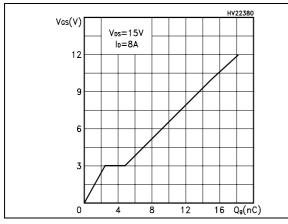


Figure 10. Normalized gate threshold voltage vs. temperature n-ch

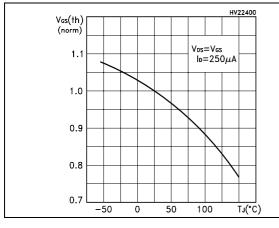


Figure 12. Source-drain diode forward characteristics n-ch

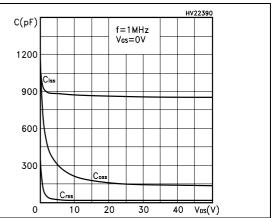


Figure 11. Normalized on resistance vs. temperature n-ch

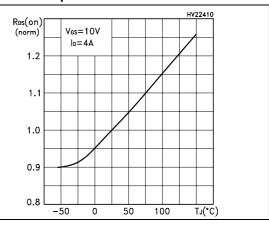


Figure 13. Normalized breakdown voltage vs. temperature n-ch

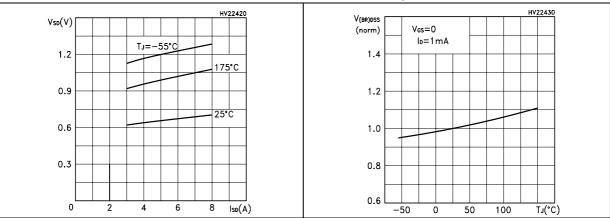
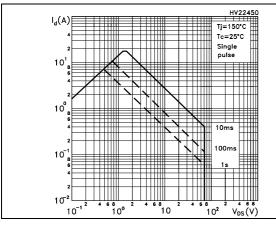
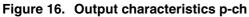


Figure 14. Safe operating area p-ch





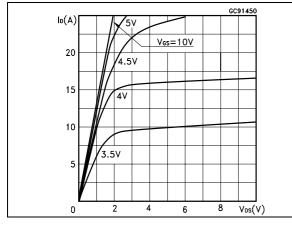


Figure 18. Transconductance p-ch

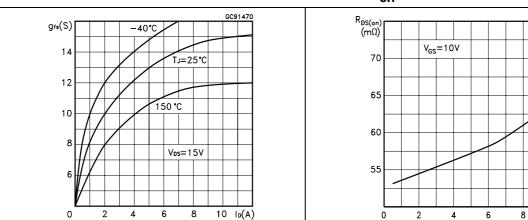


Figure 15. Thermal impedance p-ch

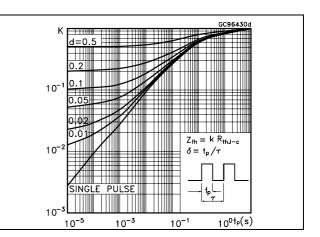


Figure 17. Transfer characteristics p-ch

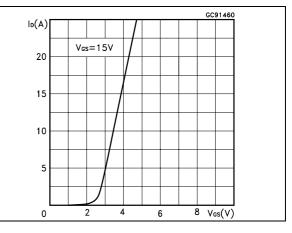


Figure 19. Static drain-source on resistance pch

GC91480

 $I_D(A)$

57



Figure 20. Gate charge vs. gate-source voltage Figure 21. Capacitance variations p-ch p-ch

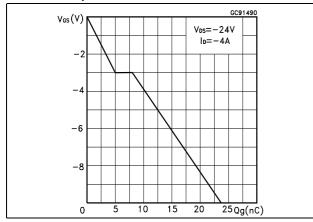


Figure 22. Normalized gate threshold voltage vs. temperature p-ch

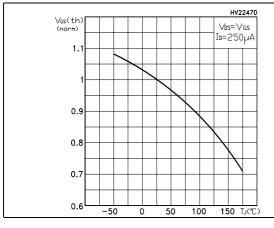


Figure 24. Source-drain diode forward characteristics p-ch

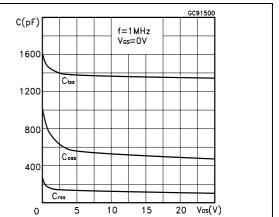


Figure 23. Normalized on resistance vs. temperature p-ch

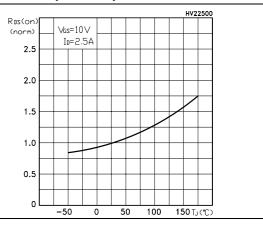
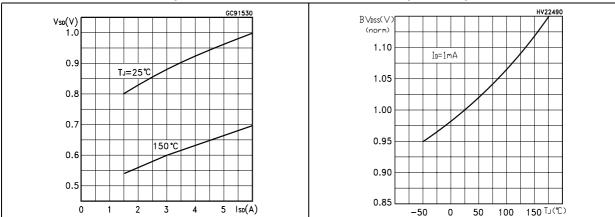
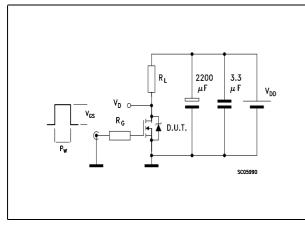


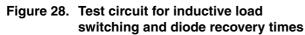
Figure 25. Normalized breakdown voltage vs. temperature p-ch

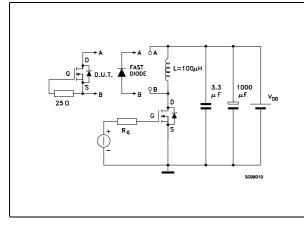


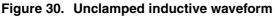
3 Test circuit

Figure 26. Switching times test circuit for resistive load



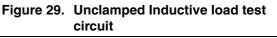


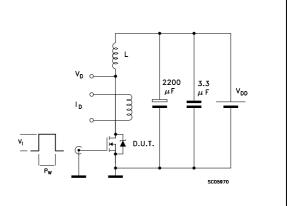


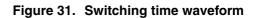


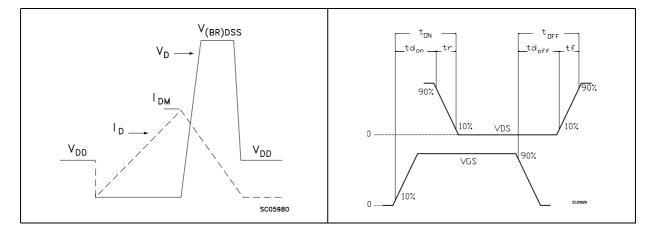
V DD 12V ‡7K Ω 1ΚΩ **⊥**100nF I_G=CONST V₁=20V=V_{GMAX} 100 Ω D.U.T. ¥ \cap _____2200 _____μF 2.7KΩ ۷G <u>1KΩ</u> SC06000

Figure 27. Gate charge test circuit











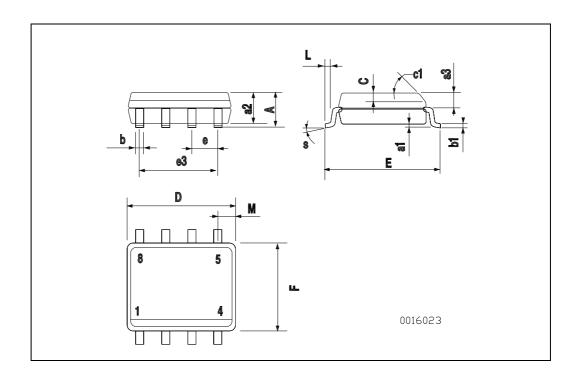
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: *www.st.com*



DIM.	mm.			inch		
	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
С	0.25		0.5	0.010		0.019
c1	45 (typ.)					
D	4.8		5.0	0.188		0.196
Е	5.8		6.2	0.228		0.244
е		1.27			0.050	
e3		3.81			0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
М			0.6			0.023

SO-8 MECHANICAL DATA



5 Revision history

Date	Revision	Changes
17-Sep-2004	1	First revision
31-Oct-2006	2	The document has been reformatted
30-Jan-2007	3	typo mistake on Table 2.
23-Jul-2007	4	Figure 14 has been updated



Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2007 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan -Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

